

# Introduction to CMOS VLSI Design

## Lecture 0: Introduction

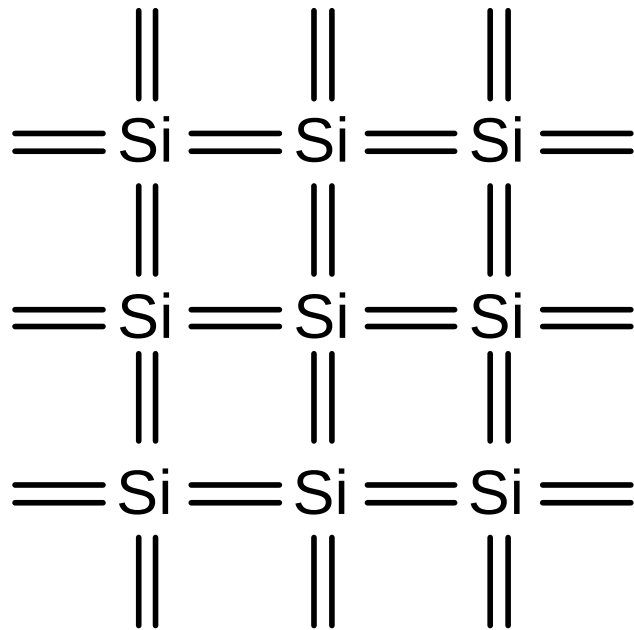
# Introduction (See Wikipedia)

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- ❑ Integrated circuits: many transistors on one chip.
- ❑ *Very Large Scale Integration (VLSI)*: very many
- ❑ *Complementary Metal Oxide Semiconductor*
  - Fast, cheap, low power transistors
- ❑ Today: How to build your own simple CMOS chip
  - CMOS transistors
  - Building logic gates from transistors
  - Transistor layout and fabrication
- ❑ Rest of the course: How to build a good CMOS chip

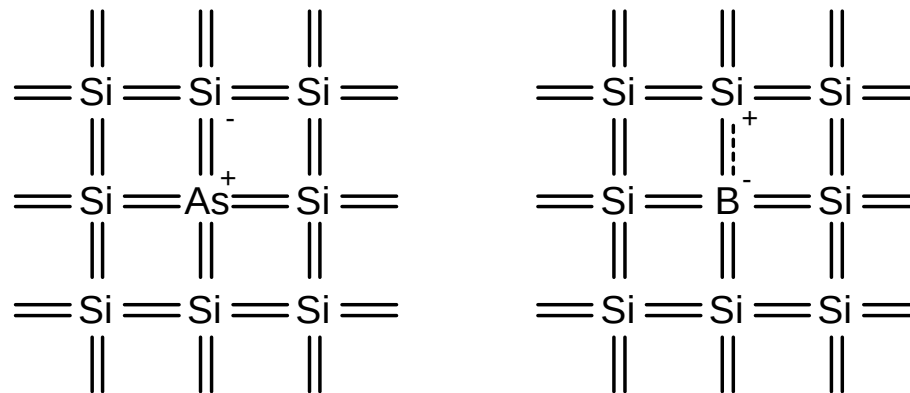
# Silicon Lattice

- ❑ Transistors are built on a silicon substrate
- ❑ Silicon is a Group IV material
- ❑ Forms crystal lattice with bonds to four neighbors



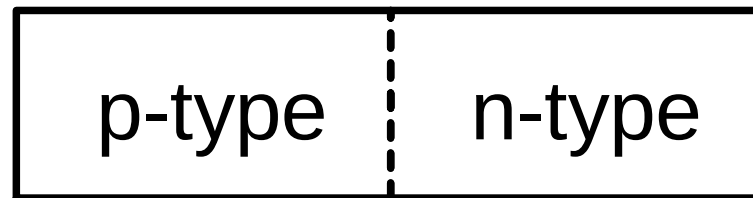
# Dopants

- ❑ Silicon is a semiconductor
- ❑ Pure silicon has no free carriers and conducts poorly
- ❑ Adding dopants increases the conductivity
- ❑ Group V: extra electron (n-type)
- ❑ Group III: missing electron, called hole (p-type)

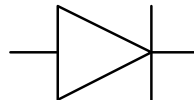


# p-n Junctions

- ❑ A junction between p-type and n-type semiconductor forms a diode.
- ❑ Current flows only in one direction

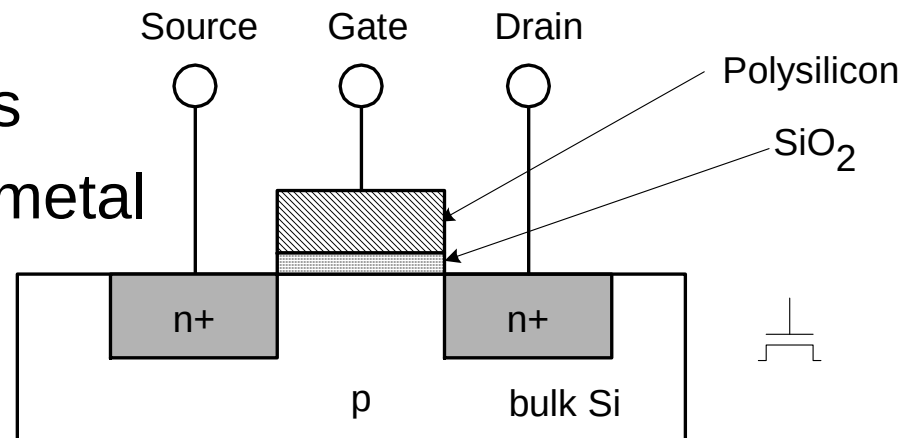


anode      cathode



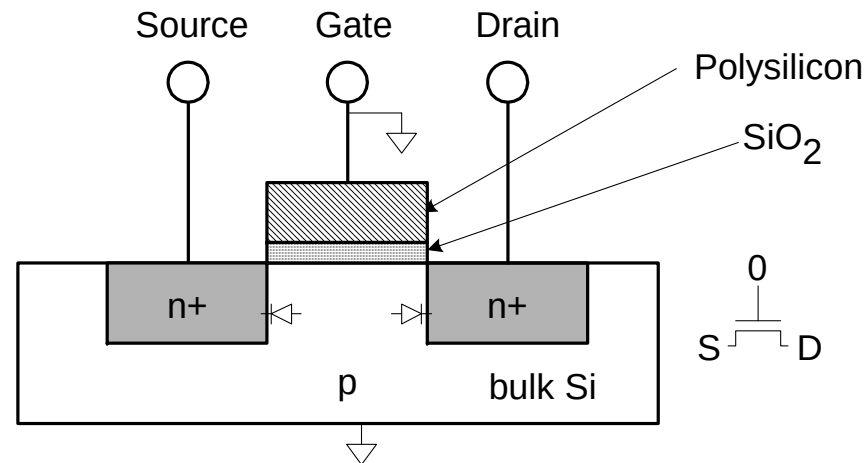
# nMOS Transistor

- ❑ Four terminals: gate, source, drain, body
- ❑ Gate – oxide – body stack looks like a capacitor
  - Gate and body are conductors
  - $\text{SiO}_2$  (oxide) is a very good insulator
  - Called metal – oxide – semiconductor (MOS) capacitor
  - Even though gate is no longer made of metal



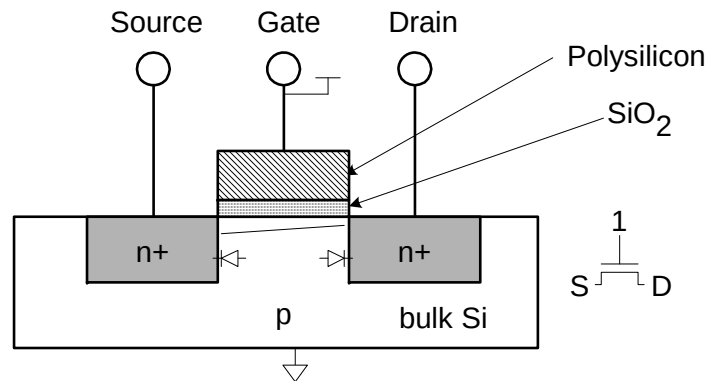
# nMOS Operation

- ❑ Body is commonly tied to ground (0 V)
- ❑ When the gate is at a low voltage:
  - P-type body is at low voltage
  - Source-body and drain-body diodes are OFF
  - No current flows, transistor is OFF



# nMOS Operation Cont.

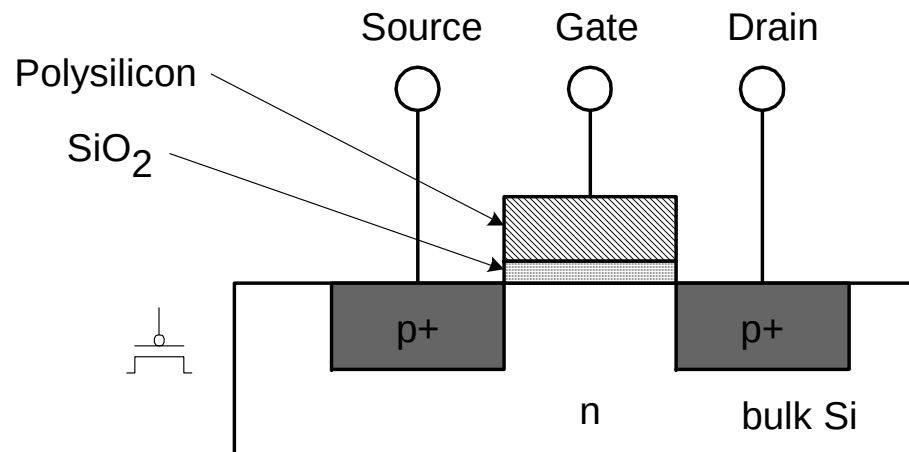
- When the gate is at a high voltage:
  - Positive charge on gate of MOS capacitor
  - Negative charge attracted to body
  - Inverts a channel under gate to n-type
  - Now current can flow through n-type silicon from source through channel to drain, transistor is ON





# pMOS Transistor

- ❑ Similar, but doping and voltages reversed
  - Body tied to high voltage ( $V_{DD}$ )
  - Gate low: transistor ON
  - Gate high: transistor OFF
  - Bubble indicates inverted behavior

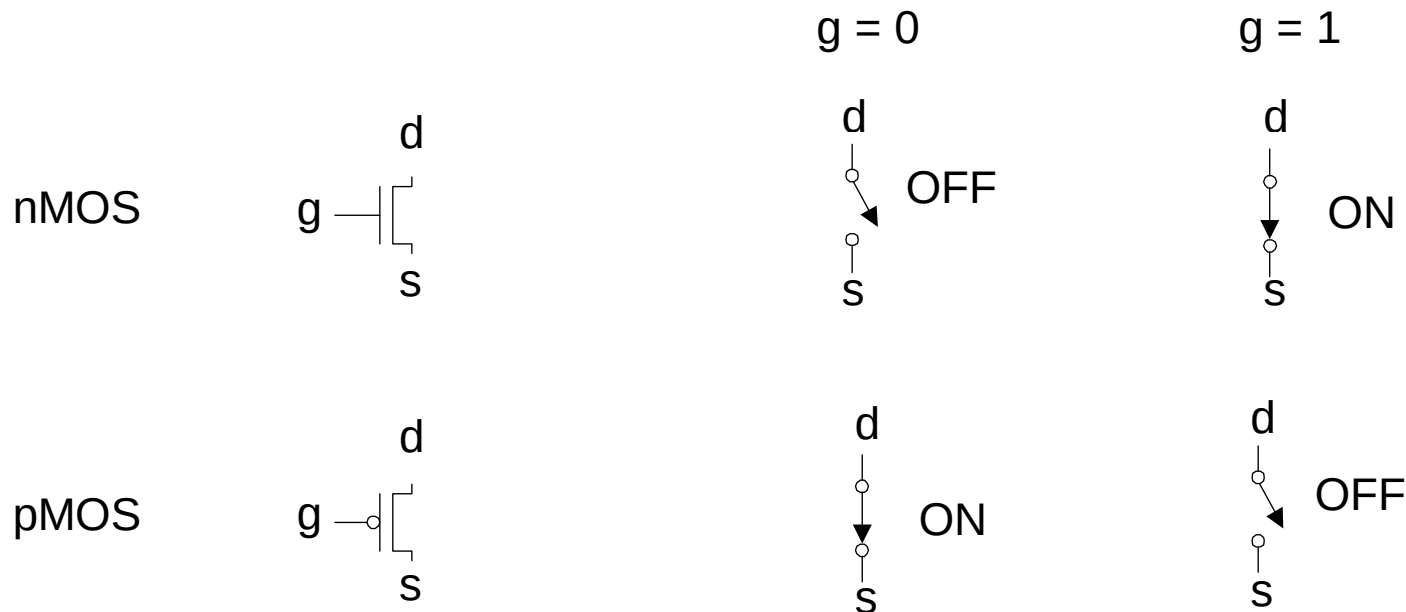


# Power Supply Voltage

- ❑  $\text{GND} = 0 \text{ V}$
- ❑ In 1980's,  $V_{\text{DD}} = 5\text{V}$
- ❑  $V_{\text{DD}}$  has decreased in modern processes
  - High  $V_{\text{DD}}$  would damage modern tiny transistors
  - Lower  $V_{\text{DD}}$  saves power
- ❑  $V_{\text{DD}} = 3.3, 2.5, 1.8, 1.5, 1.2, 1.0, \dots$

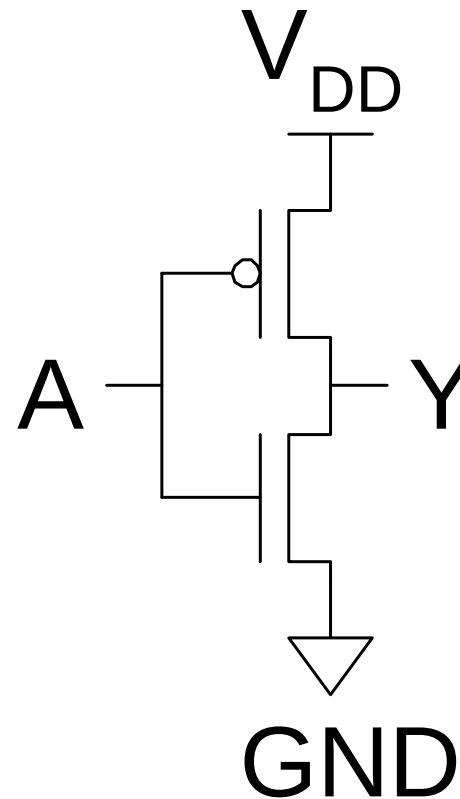
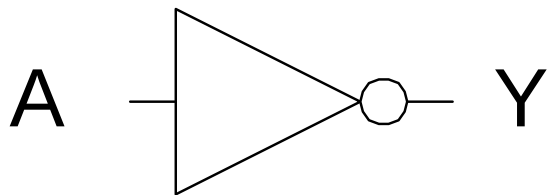
# Transistors as Switches

- ❑ We can view MOS transistors as electrically controlled switches
- ❑ Voltage at gate controls path from source to drain



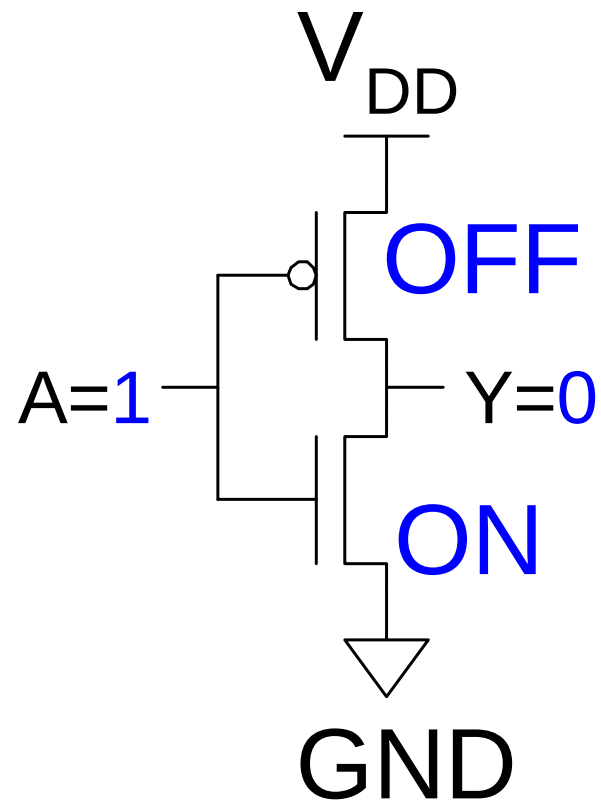
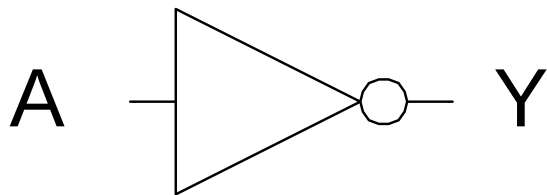
# CMOS Inverter

| A | Y |
|---|---|
| 0 |   |
| 1 |   |



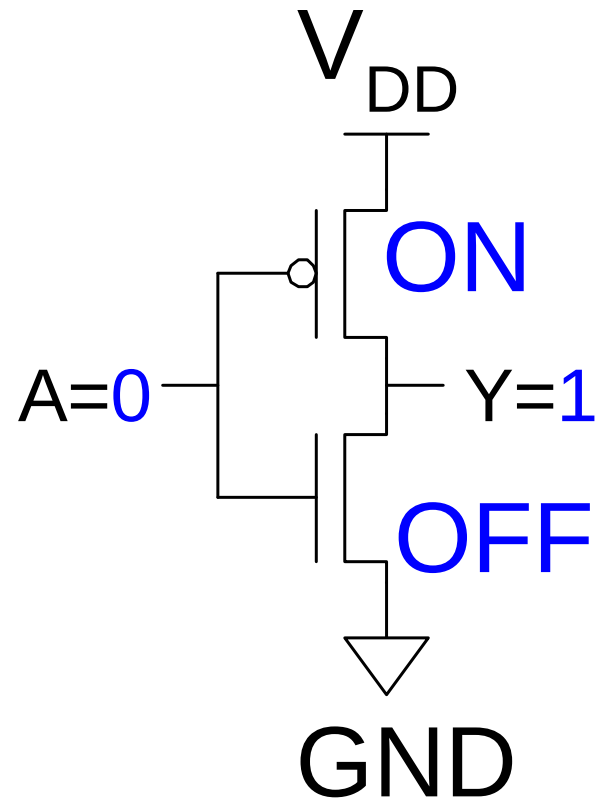
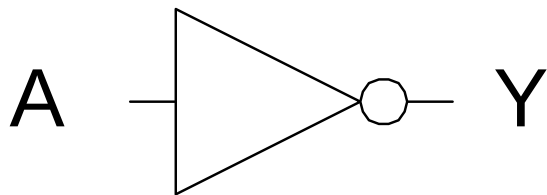
# CMOS Inverter

| A | Y |
|---|---|
| 0 |   |
| 1 | 0 |



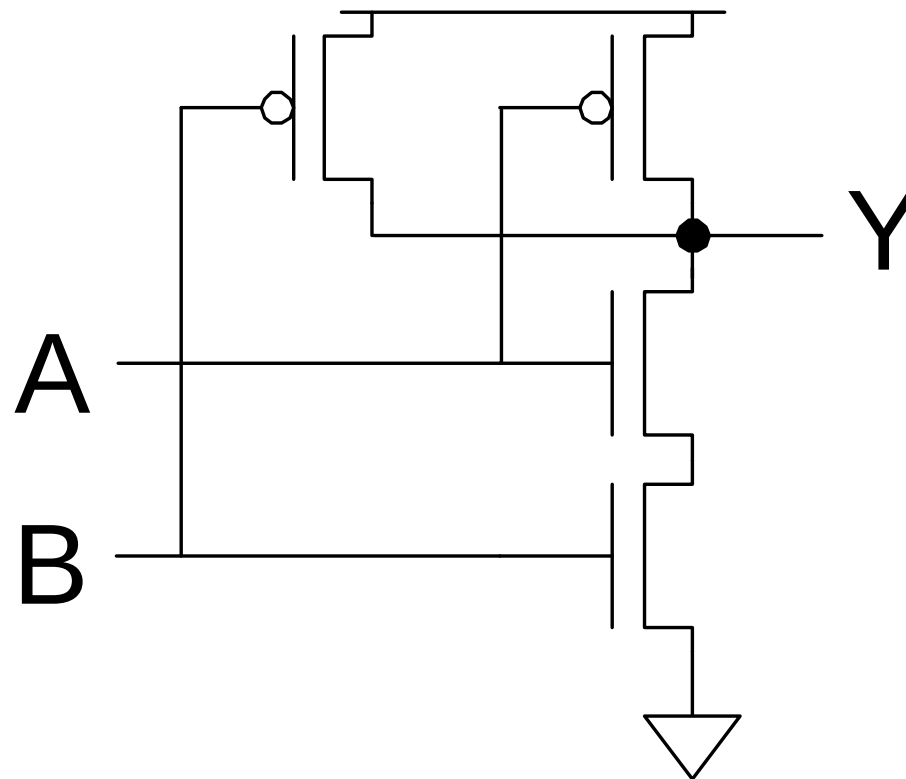
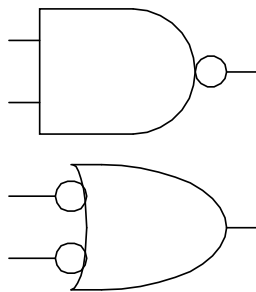
# CMOS Inverter

| A | Y |
|---|---|
| 0 | 1 |
| 1 | 0 |



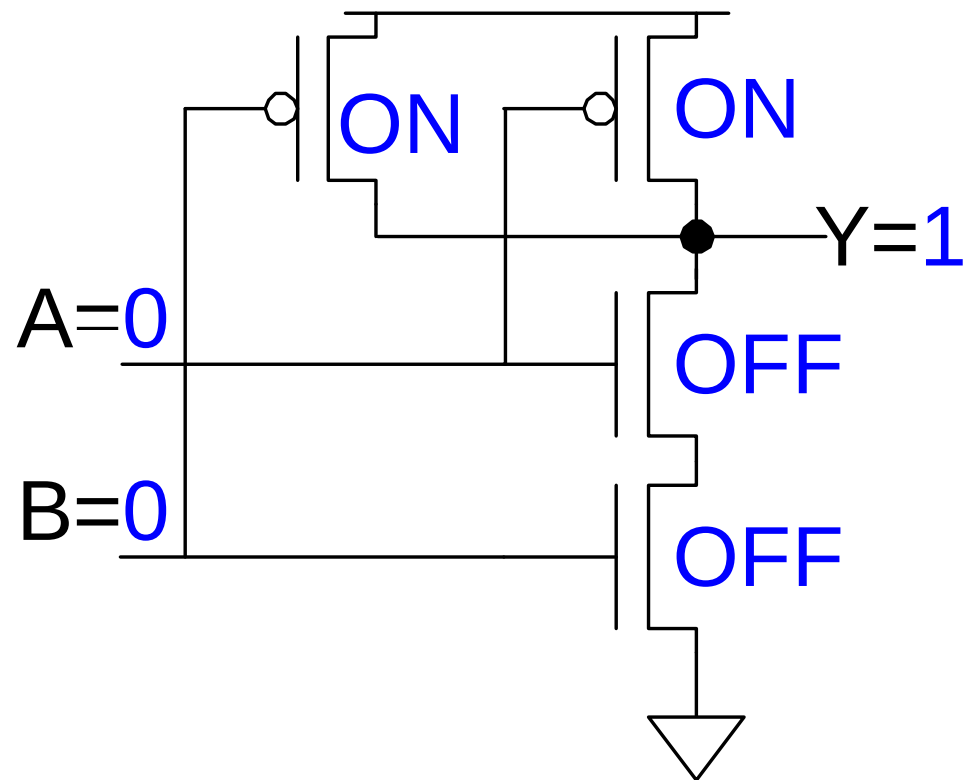
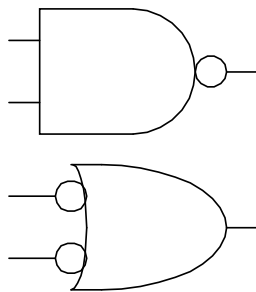
# CMOS NAND Gate

| A | B | Y |
|---|---|---|
| 0 | 0 |   |
| 0 | 1 |   |
| 1 | 0 |   |
| 1 | 1 |   |



# CMOS NAND Gate

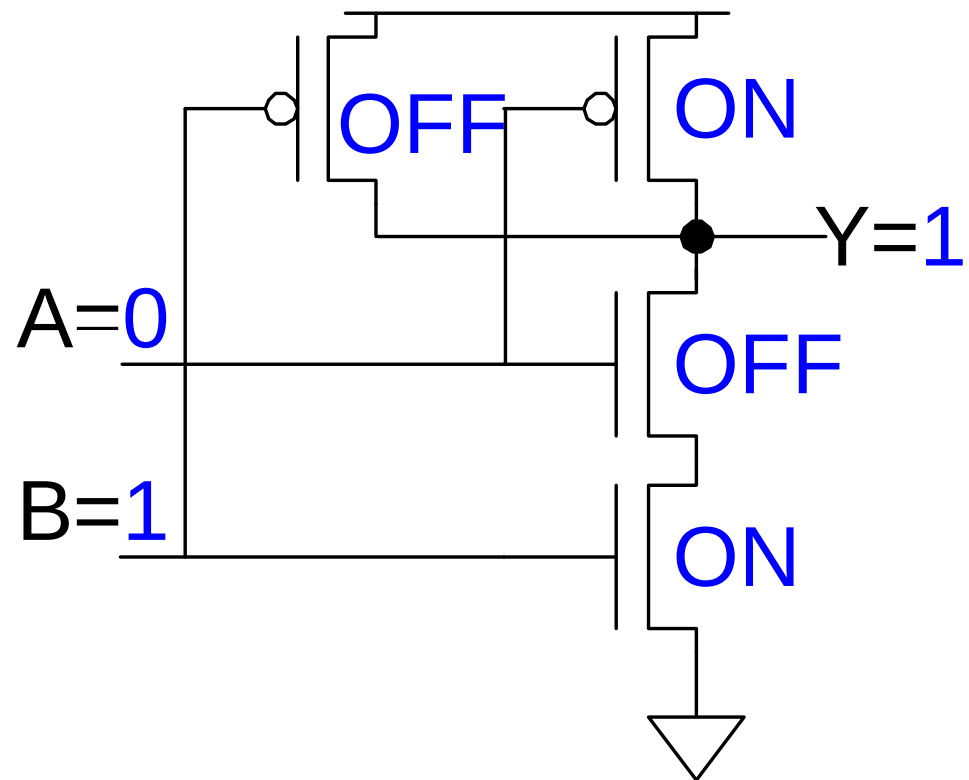
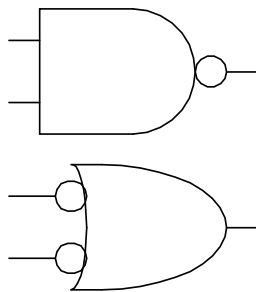
| A | B | Y |
|---|---|---|
| 0 | 0 | 1 |
| 0 | 1 |   |
| 1 | 0 |   |
| 1 | 1 |   |





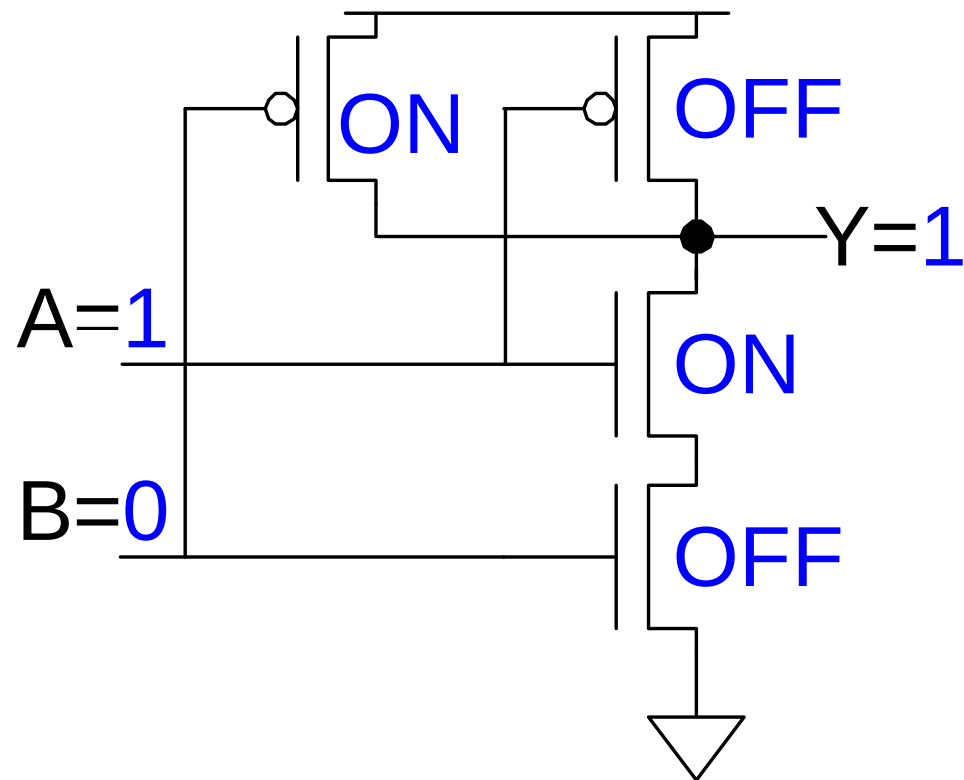
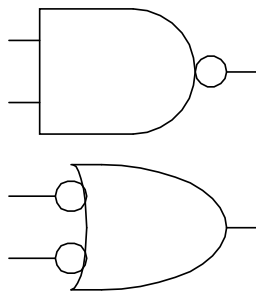
# CMOS NAND Gate

| A        | B        | Y        |
|----------|----------|----------|
| 0        | 0        | 1        |
| <b>0</b> | <b>1</b> | <b>1</b> |
| 1        | 0        |          |
| 1        | 1        |          |



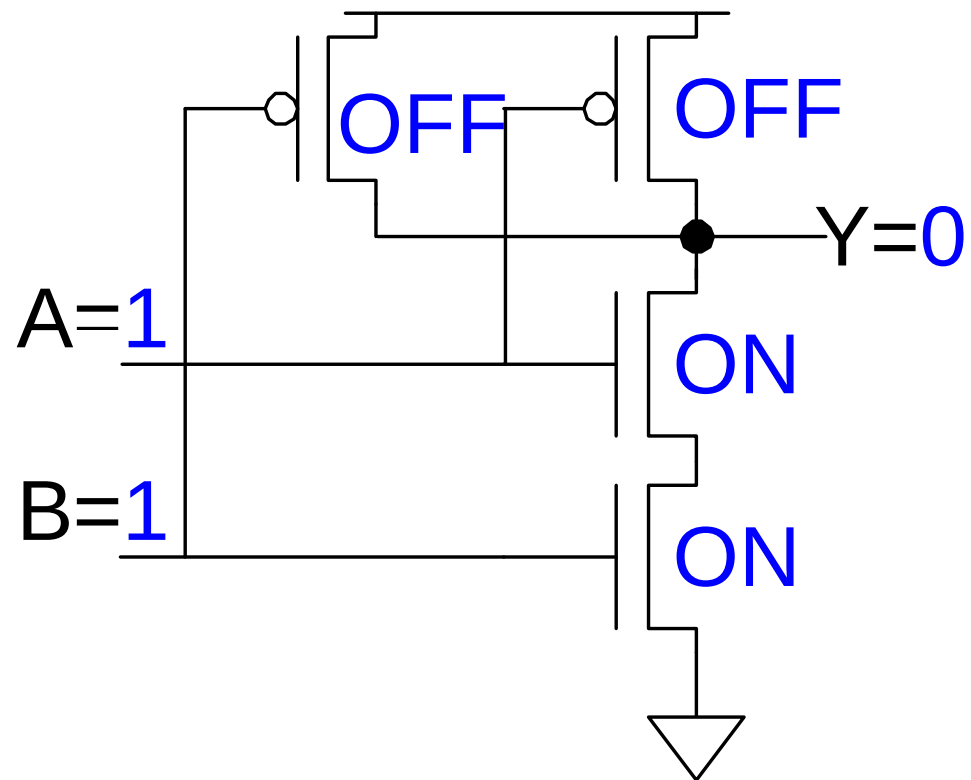
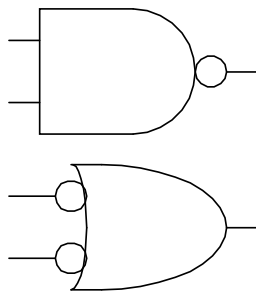
# CMOS NAND Gate

| A        | B        | Y        |
|----------|----------|----------|
| 0        | 0        | 1        |
| 0        | 1        | 1        |
| <b>1</b> | <b>0</b> | <b>1</b> |
| 1        | 1        |          |



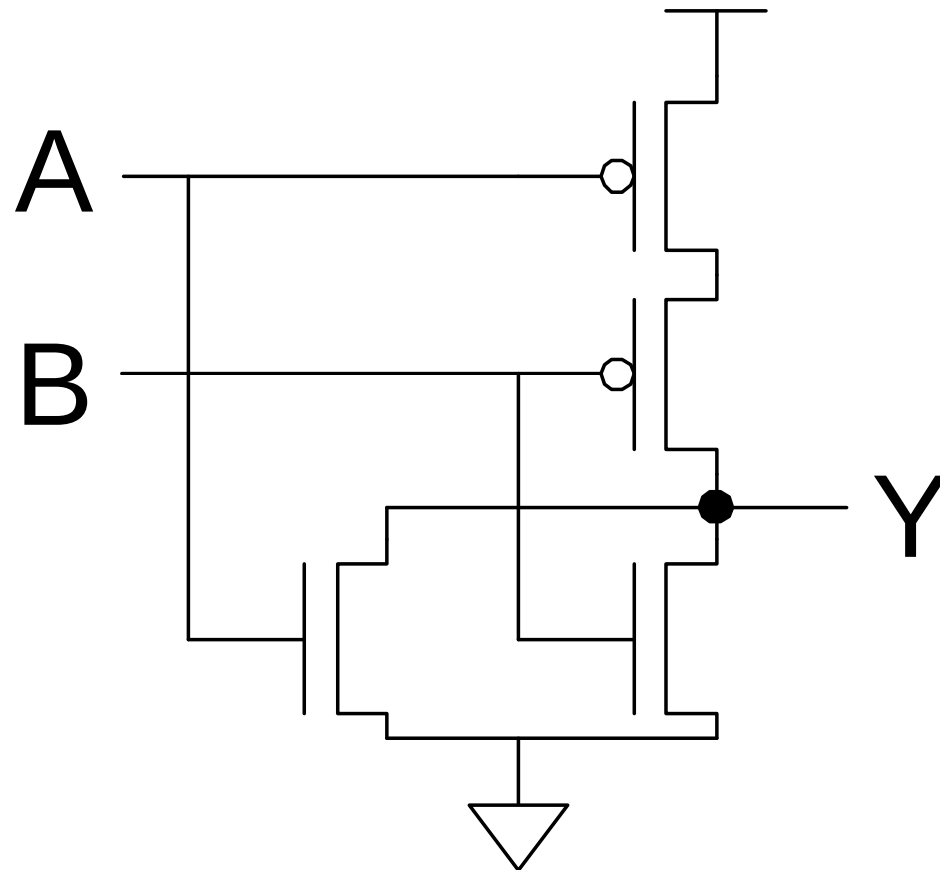
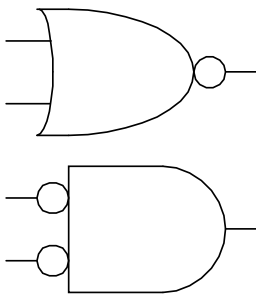
# CMOS NAND Gate

| A        | B        | Y        |
|----------|----------|----------|
| 0        | 0        | 1        |
| 0        | 1        | 1        |
| 1        | 0        | 1        |
| <b>1</b> | <b>1</b> | <b>0</b> |



# CMOS NOR Gate

| A | B | Y |
|---|---|---|
| 0 | 0 | 1 |
| 0 | 1 | 0 |
| 1 | 0 | 0 |
| 1 | 1 | 0 |



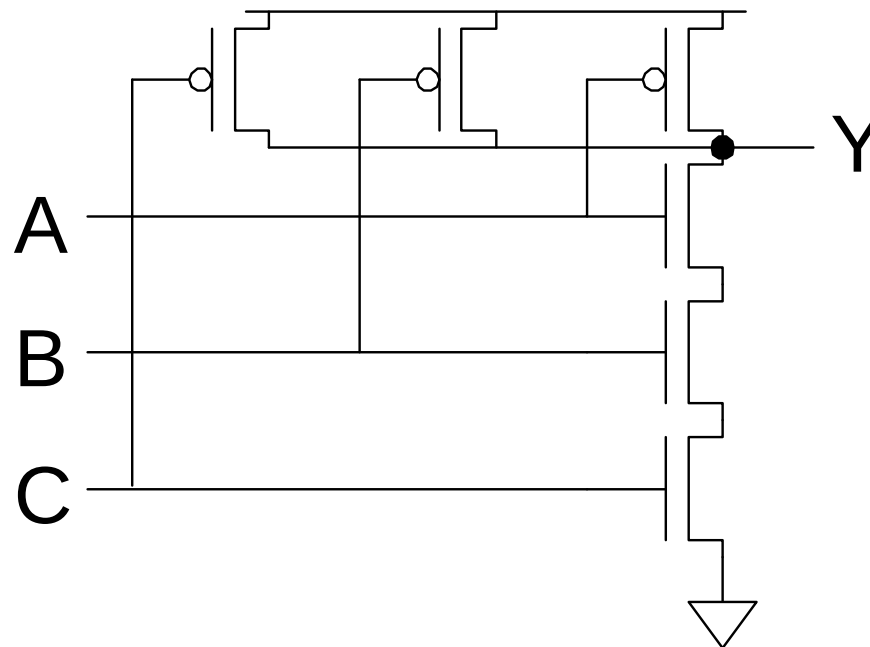
# 3-input NAND Gate

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- ☐ Y pulls low if ALL inputs are 1
- ☐ Y pulls high if ANY input is 0

# 3-input NAND Gate

- ❑ Y pulls low if ALL inputs are 1
- ❑ Y pulls high if ANY input is 0



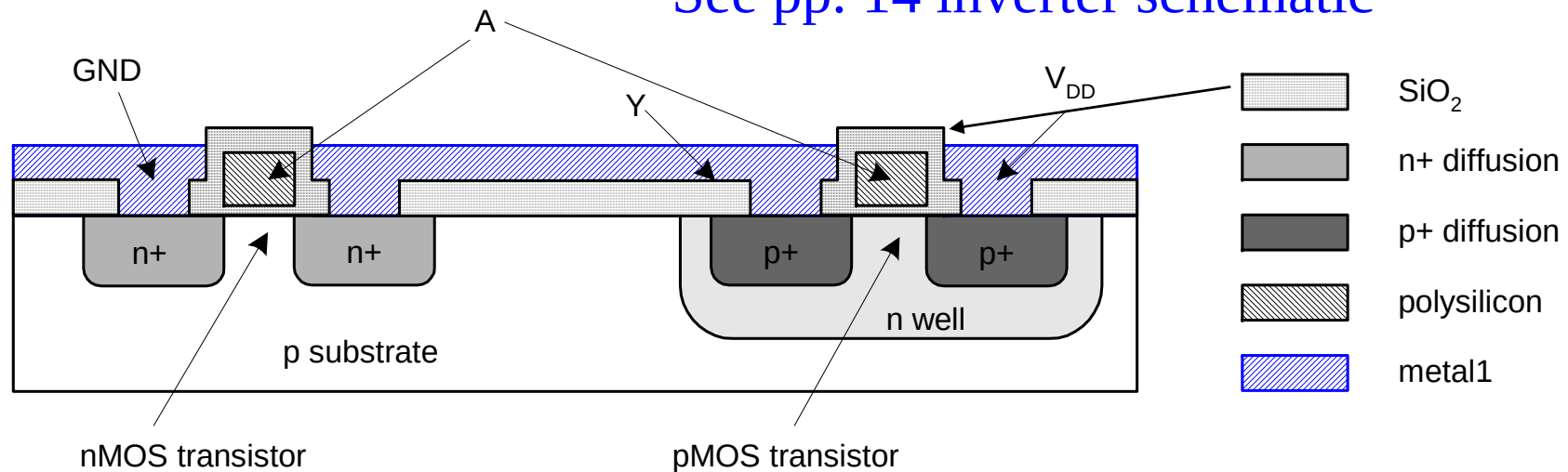
# CMOS Fabrication

- ❑ CMOS transistors are fabricated on silicon wafer
- ❑ Lithography process similar to printing press
- ❑ On each step, different materials are deposited or etched
- ❑ Easiest to understand by viewing both top and cross-section of wafer in a simplified manufacturing process

# Inverter Cross-section

- ❑ Typically use p-type substrate for nMOS transistors
- ❑ Requires n-well for body of pMOS transistors

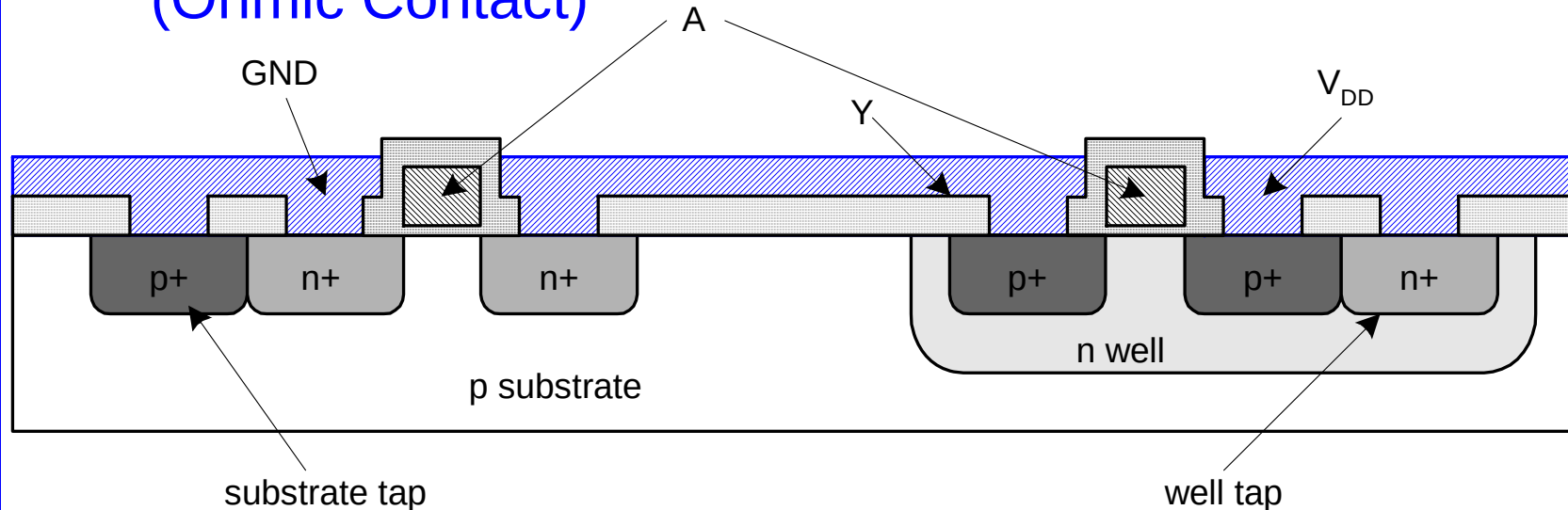
See pp. 14 inverter schematic





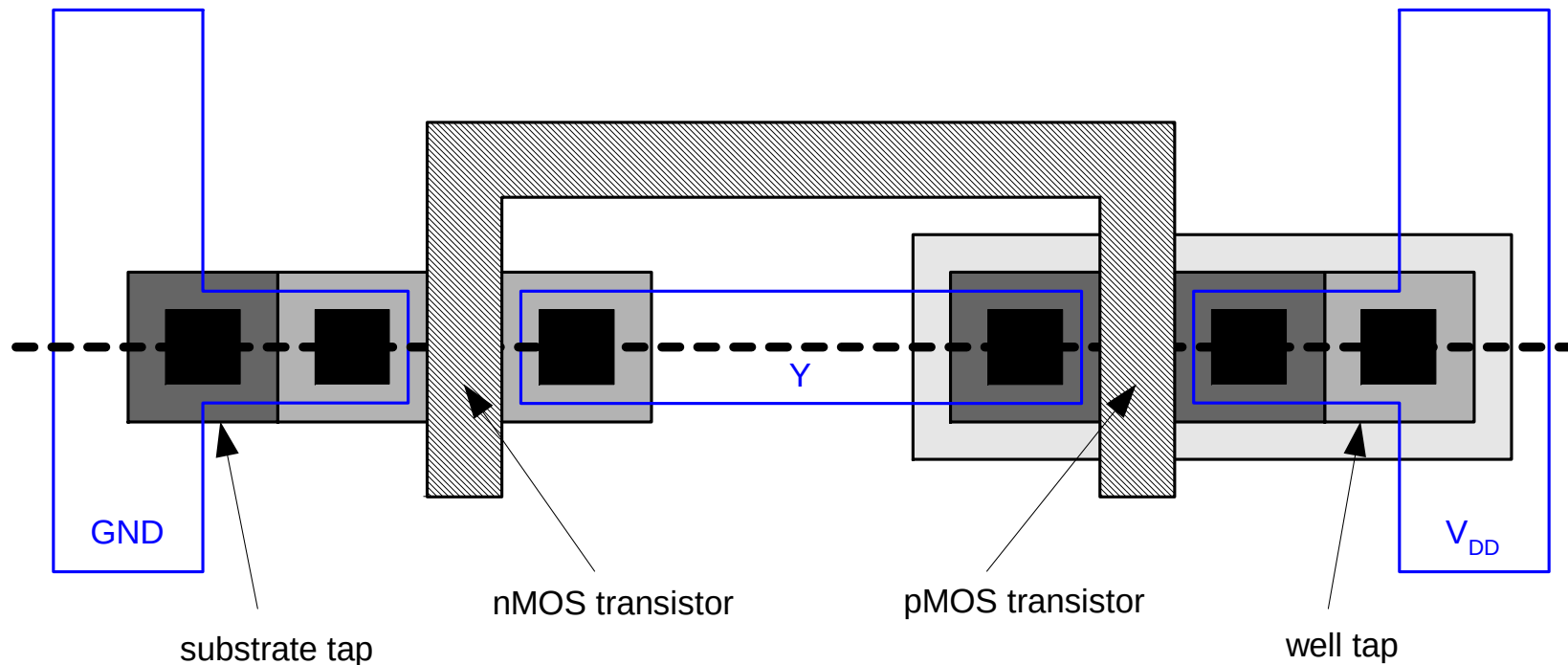
# Well and Substrate Taps

- ❑ Substrate must be tied to GND and n-well to  $V_{DD}$
- ❑ Metal to lightly-doped semiconductor forms poor connection called Schottky Diode
- ❑ Use heavily doped well and substrate contacts / taps  
(Ohmic Contact)



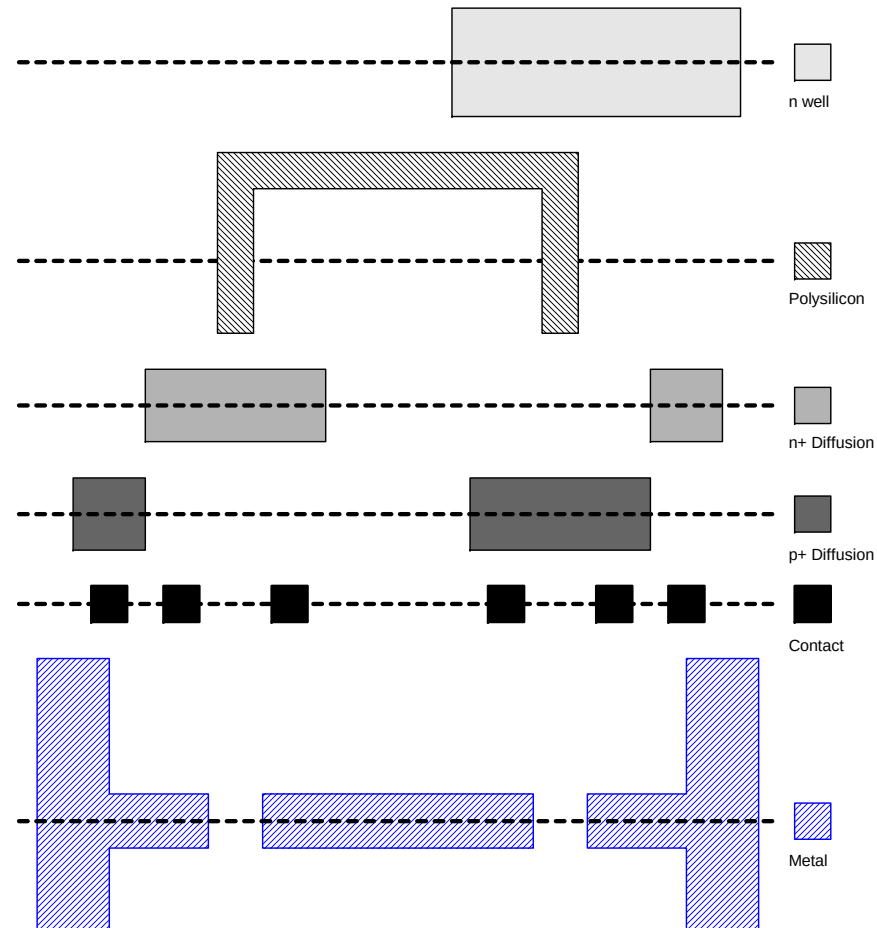
# Inverter Mask Set

- ❑ Transistors and wires are defined by *masks*
- ❑ Cross-section taken along dashed line



# Detailed Mask Views

- ❑ Six masks
  - n-well
  - Polysilicon
  - n+ diffusion
  - p+ diffusion
  - Contact
  - Metal



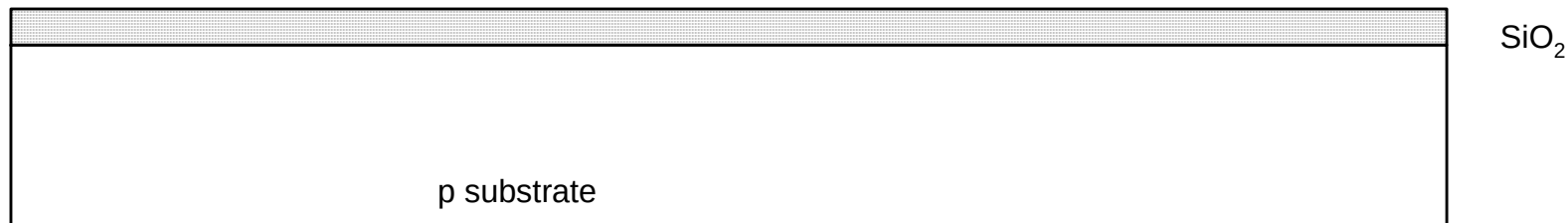
# Fabrication Steps

- ❑ Start with blank wafer
- ❑ Build inverter from the bottom up
- ❑ First step will be to form the n-well
  - Cover wafer with protective layer of  $\text{SiO}_2$  (oxide)
  - Remove layer where n-well should be built
  - Implant or diffuse n dopants into exposed wafer
  - Strip off  $\text{SiO}_2$



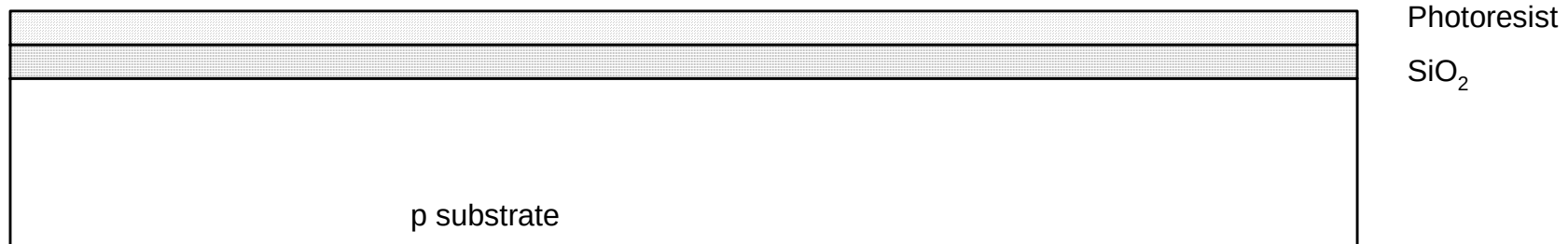
# Oxidation

- ❑ Grow  $\text{SiO}_2$  on top of Si wafer
  - 900 – 1200 C with  $\text{H}_2\text{O}$  or  $\text{O}_2$  in oxidation furnace



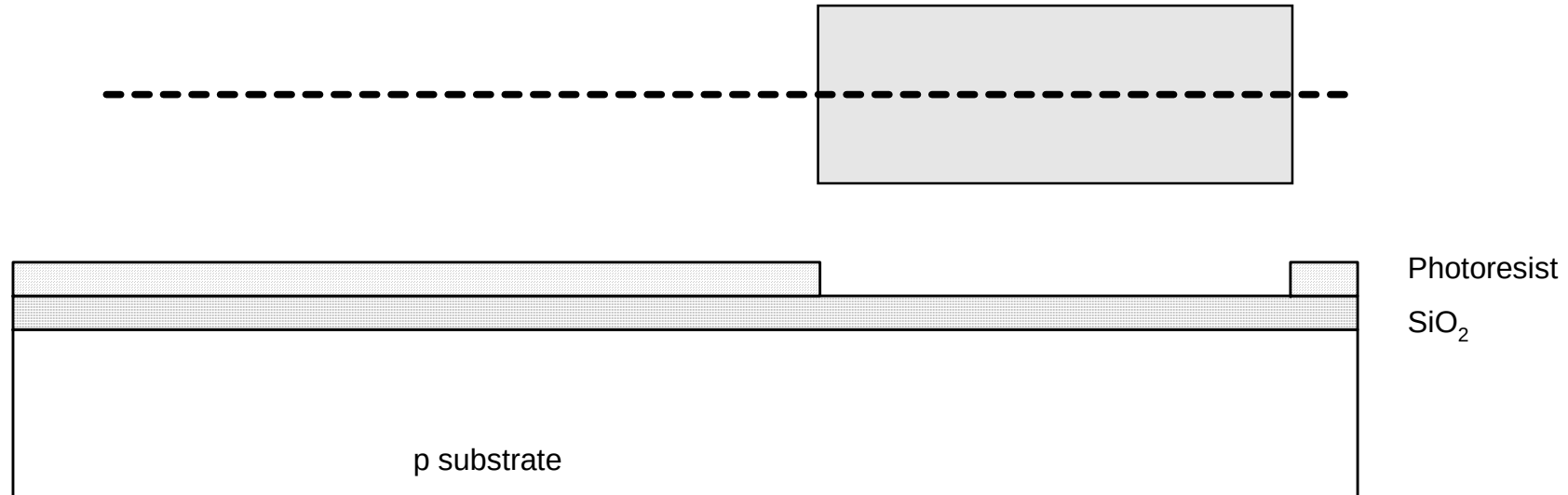
# Photoresist

- ❑ Spin on photoresist
  - Photoresist is a light-sensitive organic polymer
  - Softens where exposed to light



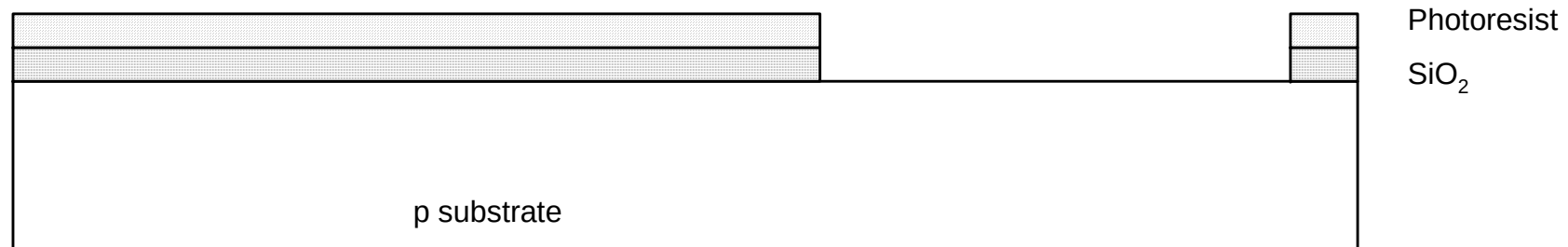
# Lithography

- ❑ Expose photoresist through n-well mask
- ❑ Strip off exposed photoresist



# Etch

- ❑ Etch oxide with hydrofluoric acid (HF)
  - Seeps ([groundwater](#), has oozed from the ground to the surface) through skin and eats bone; nasty stuff!!!
- ❑ Only attacks oxide where resist has been exposed





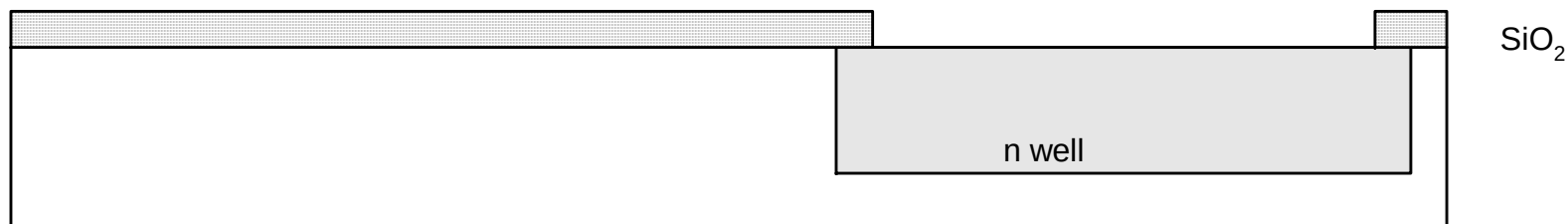
# Strip Photoresist

- ❑ Strip off remaining photoresist
  - Use mixture of acids called piranah etch
- ❑ Necessary so resist doesn't melt in next step



# n-well

- ❑ n-well is formed with diffusion or ion implantation
- ❑ Diffusion
  - Place wafer in furnace with arsenic gas
  - Heat until As atoms diffuse into exposed Si
- ❑ Ion Implantation
  - Blast wafer with beam of As ions
  - Ions blocked by  $\text{SiO}_2$ , only enter exposed Si



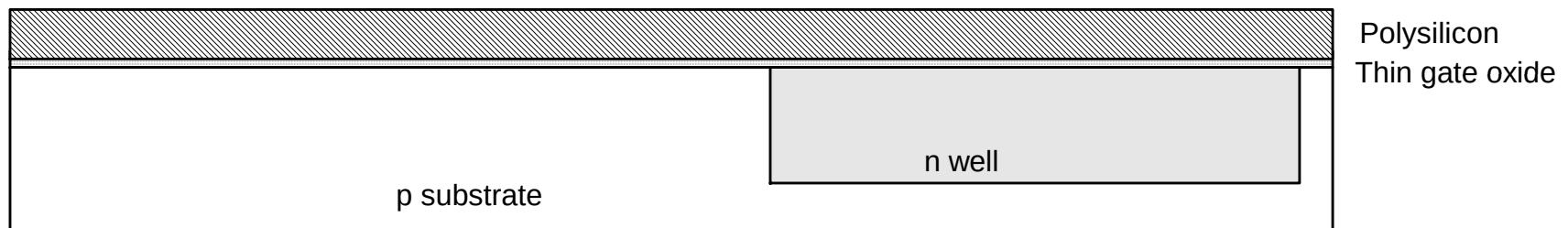
# Strip Oxide

- ❑ Strip off the remaining oxide using HF
- ❑ Back to bare wafer with n-well
- ❑ Subsequent steps involve similar series of steps



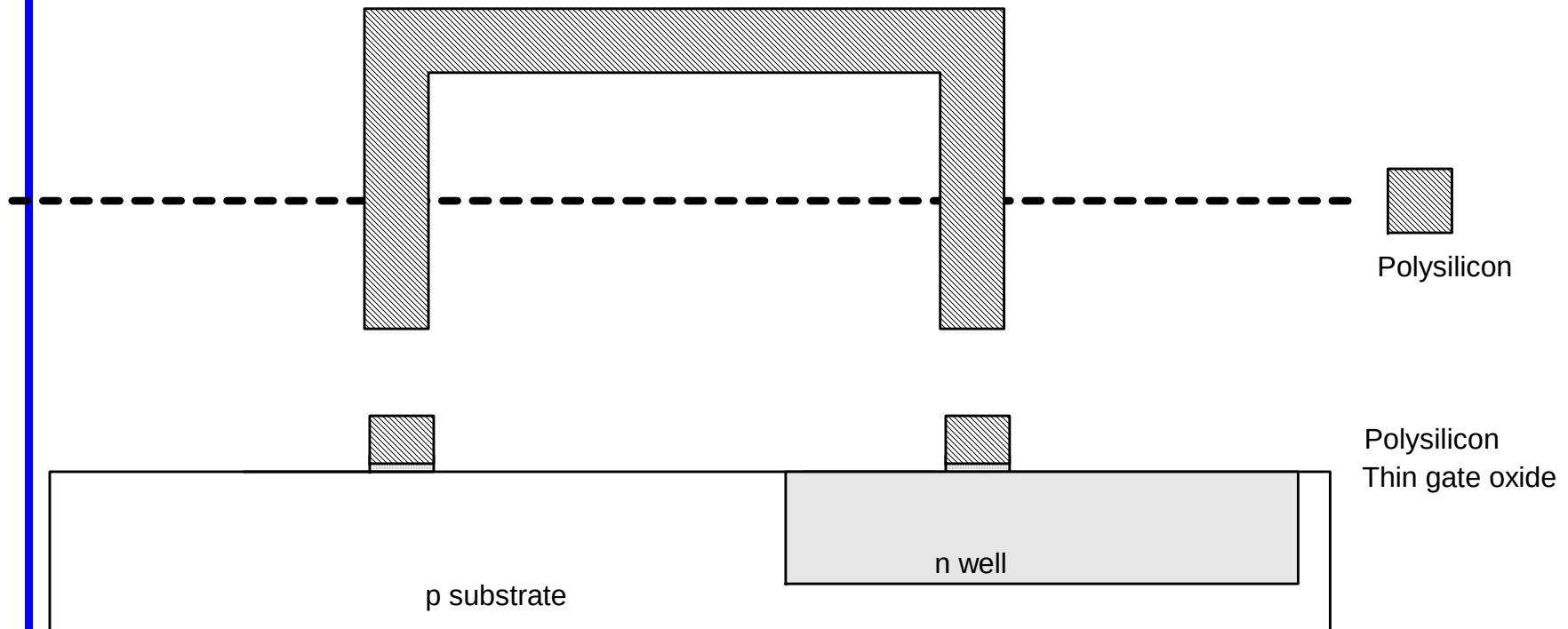
# Polysilicon

- ❑ Deposit very thin layer of gate oxide
  - $< 20 \text{ \AA}$  (6-7 atomic layers)
- ❑ Chemical Vapor Deposition (CVD) of silicon layer
  - Place wafer in furnace with Silane gas ( $\text{SiH}_4$ )
  - Forms many small crystals called polysilicon
  - Heavily doped to be good conductor



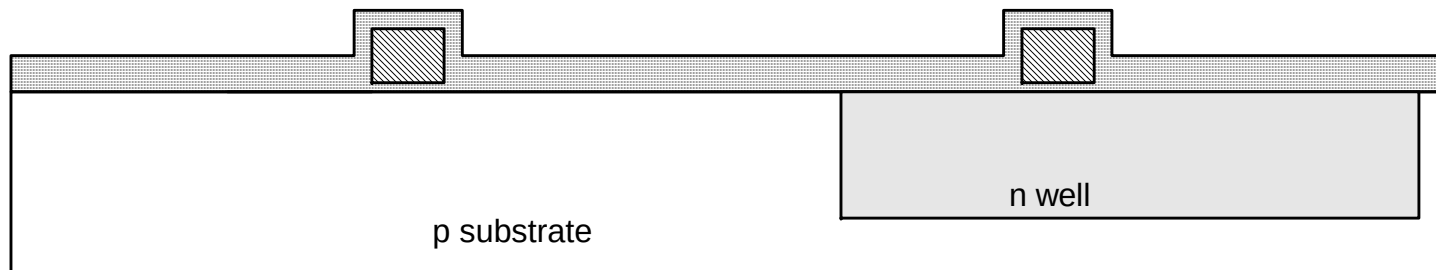
# Polysilicon Patterning

- ❑ Use same lithography process to pattern polysilicon



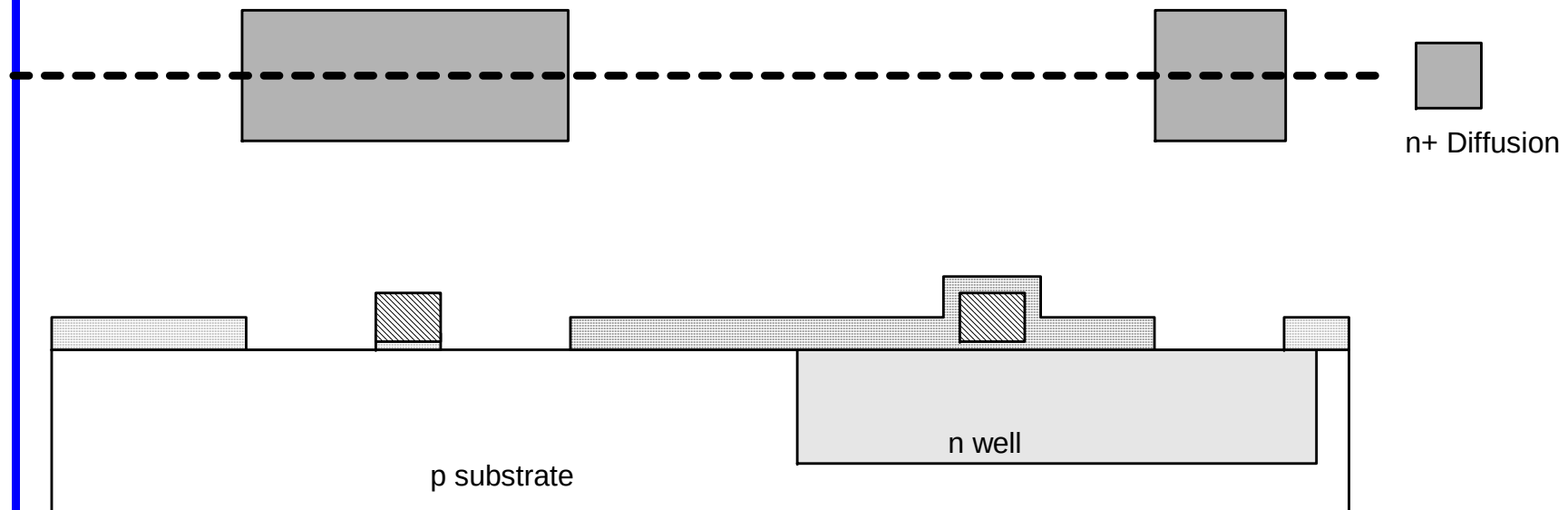
# Self-Aligned Process

- ❑ Use oxide and masking to expose where n+ dopants should be diffused or implanted
- ❑ N-diffusion forms nMOS source, drain, and n-well contact



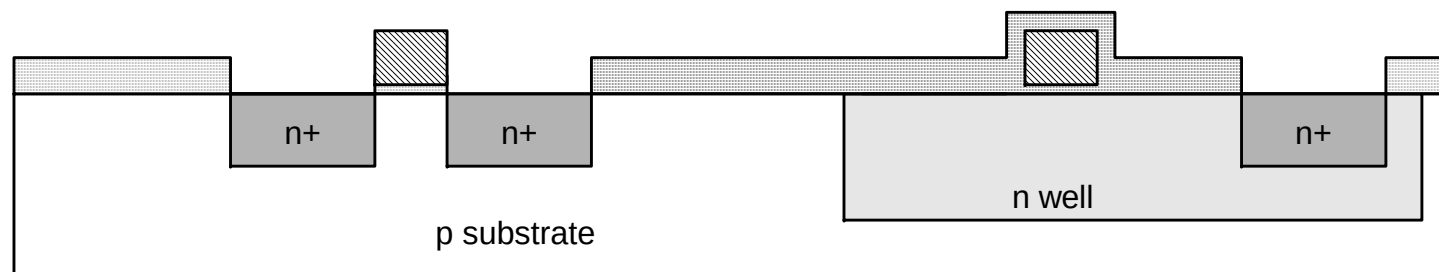
# N-diffusion

- ❑ Pattern oxide and form n+ regions
- ❑ *Self-aligned process* where gate blocks diffusion
- ❑ Polysilicon is better than metal for self-aligned gates because it doesn't melt during later processing



# N-diffusion cont.

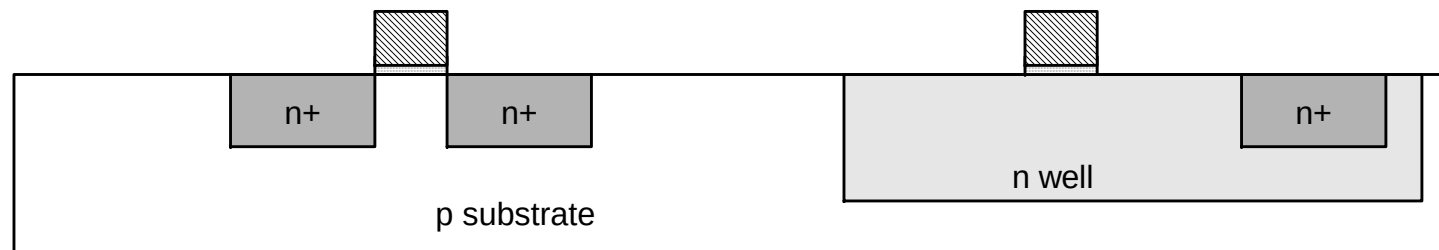
- ❑ Historically dopants were diffused
- ❑ Usually ion implantation today
- ❑ But regions are still called diffusion





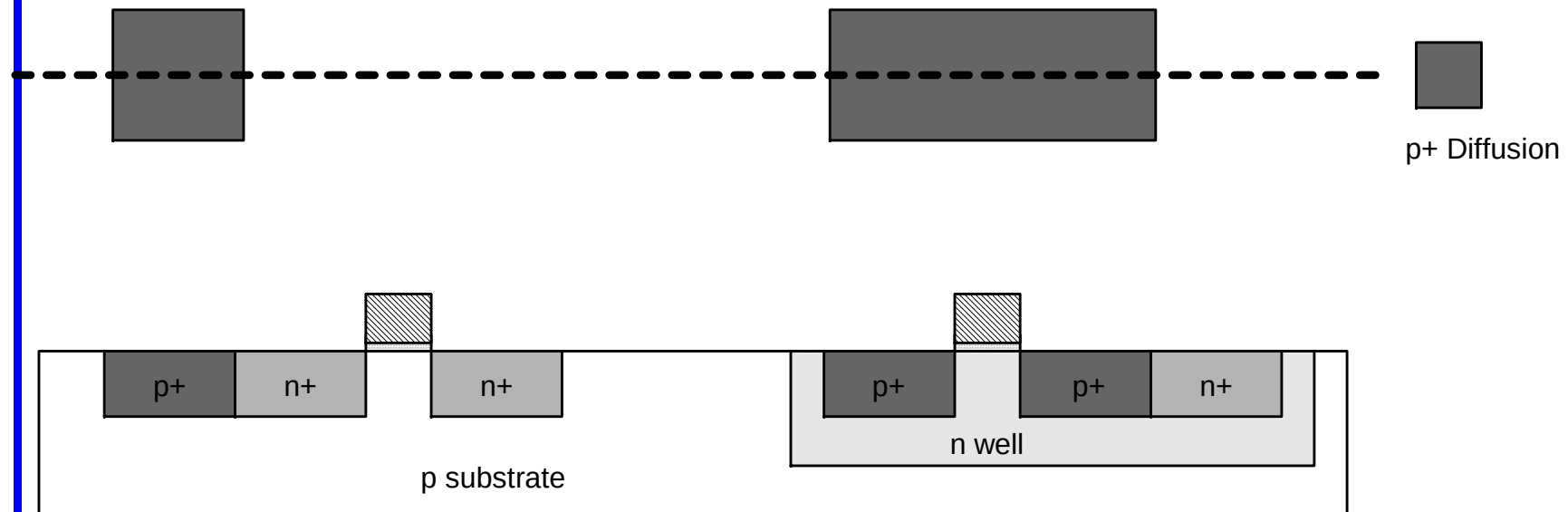
# N-diffusion cont.

- ❑ Strip off oxide to complete patterning step



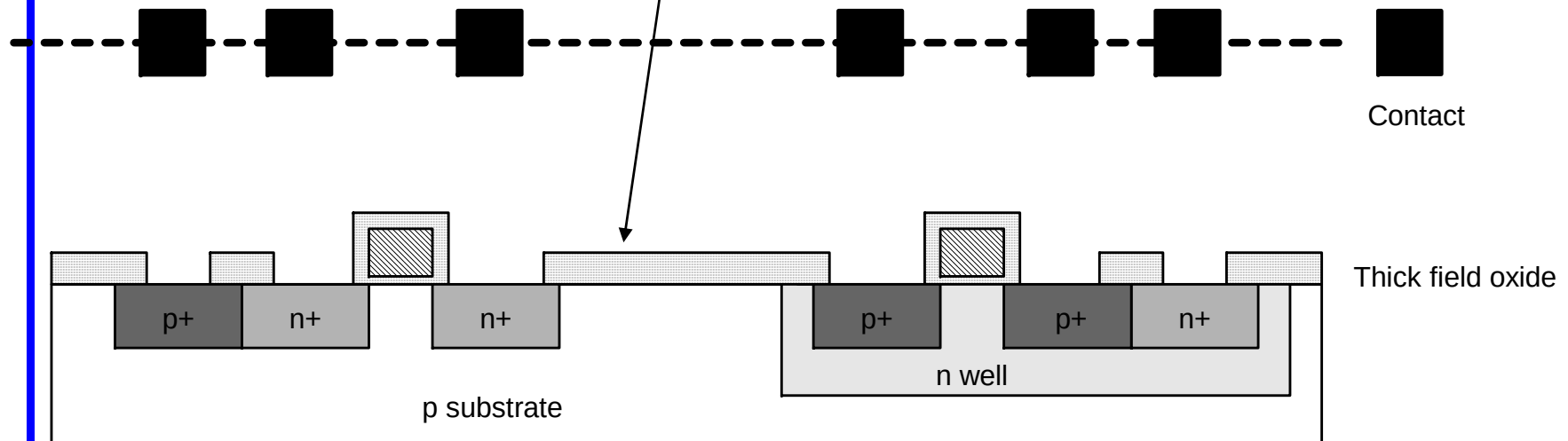
# P-Diffusion

- ❑ Similar set of steps form p+ diffusion regions for pMOS source and drain and substrate contact



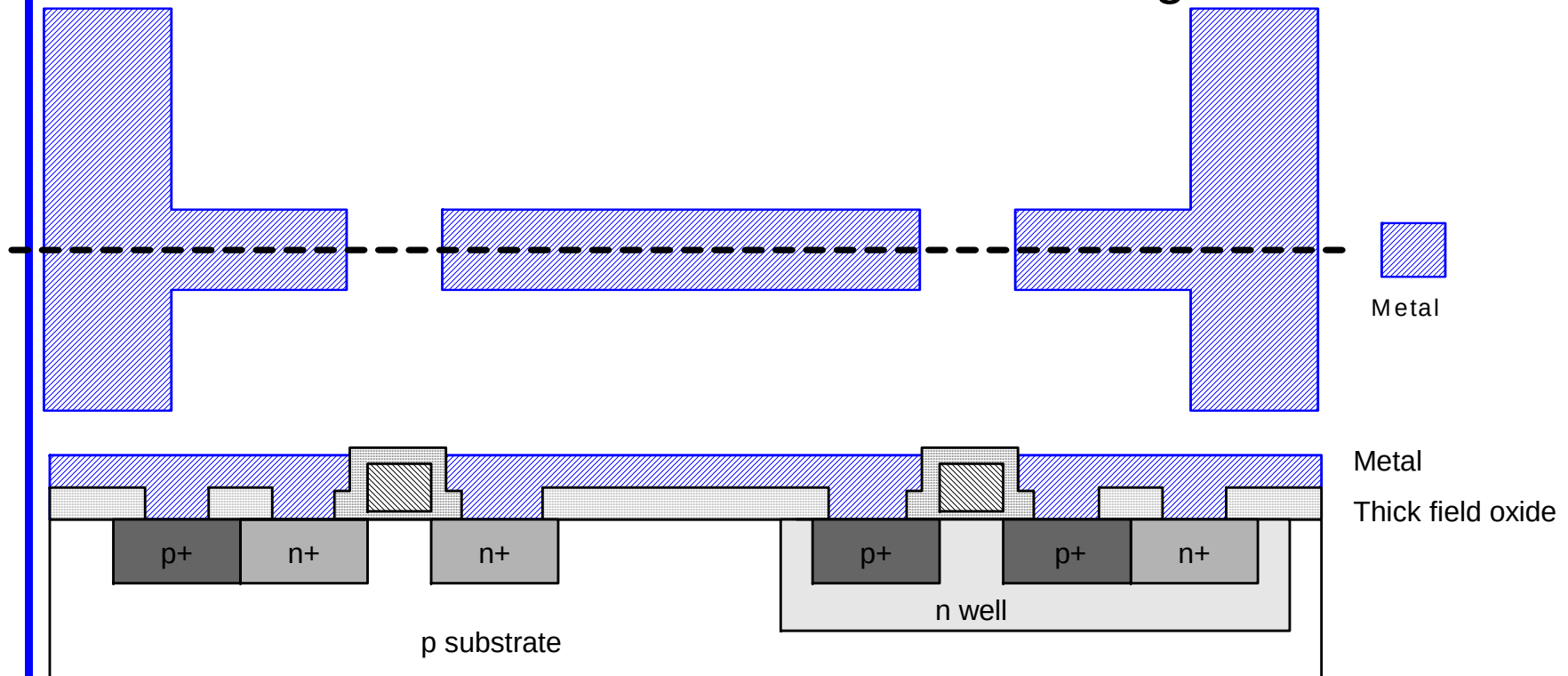
# Contacts

- ❑ Now we need to wire together the devices
- ❑ Cover chip with thick field oxide
- ❑ Etch oxide where contact cuts are needed



# Metalization

- ❑ Sputter on aluminum over whole wafer
- ❑ Pattern to remove excess metal, leaving wires

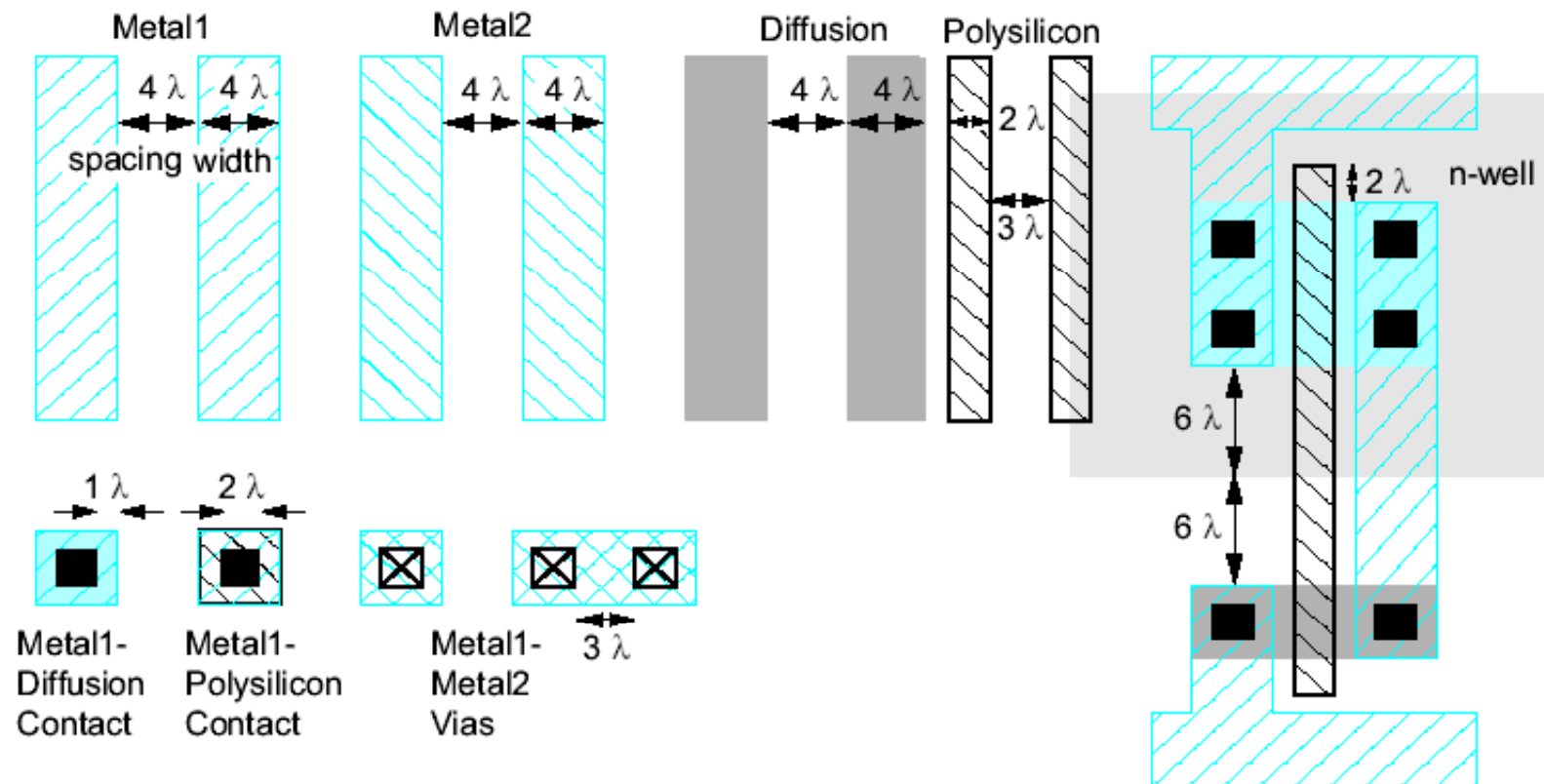


# Layout

- ❑ Chips are specified with set of masks
- ❑ Minimum dimensions of masks determine transistor size (and hence speed, cost, and power)
- ❑ Feature size  $f$  = distance between source and drain
  - Set by minimum width of polysilicon
- ❑ Feature size improves 30% every 3 years or so
- ❑ Normalize for feature size when describing design rules
- ❑ Express rules in terms of  $\lambda = f/2$ 
  - E.g.  $\lambda = 0.3 \mu\text{m}$  in  $0.6 \mu\text{m}$  process

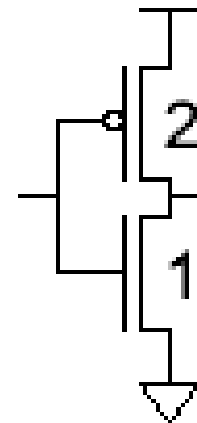
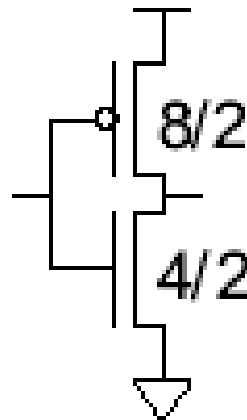
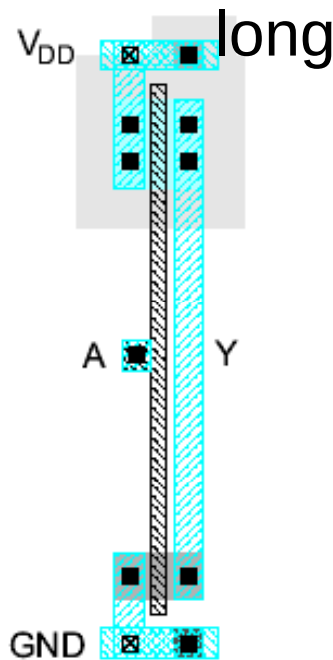
# Simplified Design Rules

- ❑ Conservative rules to get you started



# Inverter Layout

- ❑ Transistor dimensions specified as Width / Length
  - Minimum size is  $4\lambda / 2\lambda$ , sometimes called 1 unit
  - In  $f = 0.6 \mu\text{m}$  process, this is  $1.2 \mu\text{m}$  wide,  $0.6 \mu\text{m}$



# Summary

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- ❑ MOS Transistors are stack of gate, oxide, silicon
  - ❑ Can be viewed as electrically controlled switches
  - ❑ Build logic gates out of switches
  - ❑ Draw masks to specify layout of transistors
- 
- ❑ Now you know everything necessary to start designing schematics and layout for a simple chip!